## Notice of References Cited Application/Control No. 10/654,619 Examiner Van Kim T. Nguyen Applicant(s)/Patent Under Reexamination LEWIN ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,125,116	09-2000	Dighe et al.	370/395.1
*	В	US-5,999,565	12-1999	Locklear et al.	375/222
*	С	US-5,987,061	11-1999	Chen, Walter Y.	375/222
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.